

Notice of References Cited	Application/Control No. 09/805,273	Applicant(s)/Patent Under Reexamination YANG, WENG	
	Examiner Michelle Estrada	Art Unit 2823	Page 1 of 1

U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
	A	US-6,191,045 /	02-2001	Yoshigai et al.	438/714
	B	US-6,037,265 /	03-2000	Mui et al.	438/719
	C	US-6,277,763 /	08-2001	Kugimiya et al.	438/720
	D	US-5,645,683 /	07-1997	Miyamoto, Hidenobu	438/714
	E	US-6,124,212 /	09-2000	Fan et al.	438/709
	F	US-6,358,859 /	03-2002	Lo et al.	438/712
	G	US-6,521,505 /	02-2003	Kawahara, Naoyoshi	438/365
	H	US-6,159,794 /	12-2000	Yang et al.	438/257
	I	US-6,207,580 /	03-2001	Costaganna, Pascal	438/712
	J	US-4,778,563 /	10-1988	Stone, Clark S.	438/714
	K	US-5,338,398 /	08-1994	Szwejkowski et al.	438/720
	L	US-			
	M	US-			

FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N	EP 00932190 A1 /	07-1999	Europe	COSTAGANNA, PASCAL	H01L 21/321
	O	JP 2002261267 A /	09-2002	Japan	KANETAKA, HIDEUMI	H01L 29/43
	P	JP 02084723 A /	03-1990	Japan	TANAKA, KAZUHIRO	H01L 21/302
	Q					
	R					
	S					
	T					

NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	WO 96/27899, PUBLISHED 09-1996, COSTAGANNA, PASCAL.
	V	
	W	
	X	

*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
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